Deep Generative Models

Lecture 9: Generative Adversarial Networks

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- Model families
 - Autoregressive Models: $p_{\theta}(\mathbf{x}) = \prod_{i=1}^{n} p_{\theta}(x_i | \mathbf{x}_{< i})$
 - Variational Autoencoders: $p_{\theta}(\mathbf{x}) = \int p_{\theta}(\mathbf{x}, \mathbf{z}) d\mathbf{z}$
 - Normalizing Flow Models:

$$p_X(\mathbf{x}; \theta) = p_Z\left(\mathbf{f}_{\theta}^{-1}(\mathbf{x})\right) \left| \det\left(\frac{\partial \mathbf{f}_{\theta}^{-1}(\mathbf{x})}{\partial \mathbf{x}}\right) \right|$$

All the above families are based on maximizing likelihoods (or approximations)

Why maximum likelihood?

$$\hat{\theta} = \arg \max \theta \sum_{i=1}^{n} \log p_{\theta}(\mathbf{x}_i), \quad \mathbf{x}_1, \mathbf{x}_2, \cdots, \mathbf{x}_n \sim p_{data}(\mathbf{x})$$

• Optimal statistical efficiency.

- Assume sufficient model capacity, such that there exists a unique θ^{*} ∈ M that satisfies p_{θ*} = p_{data}.
- The convergence of $\hat{\theta}$ to θ^* when $n \to \infty$ is the "fastest" among all statistical methods when using maximum likelihood training.
- Higher likelihood = better lossless compression.
- Is the likelihood a good indicator of the quality of samples generated by the model?

Case 1: Optimal generative model will give best sample quality and highest test log-likelihood

For imperfect models, achieving high log-likelihoods might not always imply good sample quality, and vice-versa (Theis et al., 2016)

Towards likelihood-free learning

Case 2: Great test log-likelihoods, poor samples. E.g., For a

discrete noise mixture model $p_{ heta}(\mathbf{x}) = 0.01 p_{\text{data}}(\mathbf{x}) + 0.99 p_{\text{noise}}(\mathbf{x})$

- 99% of the samples are just noise
- Taking logs, we get a lower bound

$$\log p_{\theta}(\mathbf{x}) = \log[0.01 p_{\text{data}}(\mathbf{x}) + 0.99 p_{\text{noise}}(\mathbf{x})]$$

 $\geq \log 0.01 p_{\text{data}}(\mathbf{x}) = \log p_{\text{data}}(\mathbf{x}) - \log 100$

- For expected likelihoods, we know that
 - Lower bound

 $E_{p_{\text{data}}}[\log p_{\theta}(\mathbf{x})] \geq E_{p_{\text{data}}}[\log p_{ ext{data}}(\mathbf{x})] - \log 100$

• Upper bound (via non-negativity of KL)

 $E_{p_{ ext{data}}}[\log p_{ ext{data}}(\mathbf{x}))] \geq E_{p_{ ext{data}}}[\log p_{ heta}(\mathbf{x})]$

 As we increase the dimension of x, absolute value of log p_{data}(x) increases proportionally but log 100 remains constant. Hence, E<sub>p_{data}[log p_θ(x)] ≈ E<sub>p_{data}[log p_{data}(x)] in very high dimensions
</sub></sub> **Case 3:** Great samples, poor test log-likelihoods. E.g., Memorizing training set

- Samples look exactly like the training set (cannot do better!)
- Test set will have zero probability assigned (cannot do worse!)

Takeaways:

- The above cases suggest that it might be useful to disentangle likelihoods and samples
- Likelihood-free learning consider objectives that do not depend directly on a likelihood function

Comparing distributions via samples



Given a finite set of samples from two distributions $S_1 = \{\mathbf{x} \sim P\}$ and $S_2 = \{\mathbf{x} \sim Q\}$, how can we tell if these samples are from the same distribution? (i.e., P = Q?)

- Given $S_1 = {\mathbf{x} \sim P}$ and $S_2 = {\mathbf{x} \sim Q}$, a two-sample test considers the following hypotheses
 - Null hypothesis H_0 : P = Q
 - Alternative hypothesis H_1 : $P \neq Q$
- Test statistic T compares S_1 and S_2 e.g., difference in means, variances of the two sets of samples
- If T is larger than a threshold α , then reject H_0 otherwise we say H_0 is consistent with observation.
- Key observation: Test statistic is likelihood-free since it does not involve the densities *P* or *Q* (only samples)

Generative modeling and two-sample tests



- A priori we assume direct access to $S_1 = \mathcal{D} = \{\mathbf{x} \sim p_{\text{data}}\}$
- In addition, we have a model distribution $p_{ heta}$
- Assume that the model distribution permits efficient sampling (e.g., directed models). Let $S_2 = \{\mathbf{x} \sim p_{\theta}\}$
- Alternative notion of distance between distributions: Train the generative model to minimize a two-sample test objective between S₁ and S₂

Two-Sample Test via a Discriminator

• Finding a two-sample test objective in high dimensions is hard



- In the generative model setup, we know that S_1 and S_2 come from different distributions p_{data} and p_{θ} respectively
- Key idea: Learn a statistic that maximizes a suitable notion of distance between the two sets of samples S₁ and S₂

Two-Sample Test via a Discriminator



- Two-Sample Test via a Discriminator
 - Any function (e.g., neural network) which tries to distinguish "real" samples from the dataset and "fake" samples generated from the model
 - Maximizes the two-sample test objective (in support of the alternative hypothesis $p_{\rm data} \neq p_{ heta}$)

• Training objective for discriminator:

$$\max_{D} V(G, D) = E_{\mathbf{x} \sim p_{\text{data}}}[\log D(\mathbf{x})] + E_{\mathbf{x} \sim p_G}[\log(1 - D(\mathbf{x}))]$$

- For a fixed generator *G*, the discriminator is performing binary classification with the cross entropy objective
 - Assign probability 1 to true data points $\mathbf{x} \sim p_{\mathrm{data}}$
 - Assign probability 0 to fake samples $\mathbf{x} \sim p_G$
- Optimal discriminator

$$D_G^*(\mathbf{x}) = rac{p_{ ext{data}}(\mathbf{x})}{p_{ ext{data}}(\mathbf{x}) + p_G(\mathbf{x})}$$

Generative Adversarial Networks

• A two player minimax game between a **generator** and a **discriminator**



Generator

- Directed, latent variable model with a deterministic mapping between z and x given by G_θ
- Minimizes a two-sample test objective (in support of the null hypothesis $p_{\rm data} = p_{\theta}$)

• Training objective for generator:

 $\min_{G} \max_{D} V(G, D) = E_{\mathbf{x} \sim p_{\text{data}}}[\log D(\mathbf{x})] + E_{\mathbf{x} \sim p_{G}}[\log(1 - D(\mathbf{x}))]$

• For the optimal discriminator $D^*_{\mathcal{G}}(\cdot)$, we have

$$V(G, D_{G}^{*}(\mathbf{x}))$$

$$= E_{\mathbf{x} \sim p_{\text{data}}} \left[\log \frac{p_{\text{data}}(\mathbf{x})}{p_{\text{data}}(\mathbf{x}) + p_{G}(\mathbf{x})} \right] + E_{\mathbf{x} \sim p_{G}} \left[\log \frac{p_{G}(\mathbf{x})}{p_{\text{data}}(\mathbf{x}) + p_{G}(\mathbf{x})} \right]$$

$$= E_{\mathbf{x} \sim p_{\text{data}}} \left[\log \frac{p_{\text{data}}(\mathbf{x})}{\frac{p_{\text{data}}(\mathbf{x}) + p_{G}(\mathbf{x})}{2}} \right] + E_{\mathbf{x} \sim p_{G}} \left[\log \frac{p_{G}(\mathbf{x})}{\frac{p_{\text{data}}(\mathbf{x}) + p_{G}(\mathbf{x})}{2}} \right] - \log 4$$

$$= \underbrace{D_{KL} \left[p_{\text{data}}, \frac{p_{\text{data}} + p_{G}}{2} \right] + D_{KL} \left[p_{G}, \frac{p_{\text{data}} + p_{G}}{2} \right]}_{2 \times \text{Jenson-Shannon Divergence (JSD)}} - \log 4$$

Jenson-Shannon Divergence

• Also called as the symmetric KL divergence

$$D_{JSD}[p,q] = \frac{1}{2} \left(D_{KL} \left[p, \frac{p+q}{2} \right] + D_{KL} \left[q, \frac{p+q}{2} \right] \right)$$

- Properties
 - $D_{JSD}[p,q] \ge 0$
 - $D_{JSD}[p,q] = 0$ iff p = q
 - $D_{JSD}[p,q] = D_{JSD}[q,p]$
 - $\sqrt{D_{JSD}[p,q]}$ satisfies triangle inequality \rightarrow Jenson-Shannon Distance
- Optimal generator for the JSD/Negative Cross Entropy GAN

$$p_G = p_{\text{data}}$$

For the optimal discriminator D^{*}_{G*}(·) and generator G^{*}(·), we have

The GAN training algorithm

- Sample minibatch of *m* training points x⁽¹⁾, x⁽²⁾, ..., x^(m) from D
- Sample minibatch of *m* noise vectors z⁽¹⁾, z⁽²⁾,..., z^(m) from *p_z*
- Update the discriminator parameters ϕ by stochastic gradient $\ensuremath{\mathbf{ascent}}$

$$\nabla_{\phi} V(G_{\theta}, D_{\phi}) = \frac{1}{m} \nabla_{\phi} \sum_{i=1}^{m} [\log D_{\phi}(\mathbf{x}^{(i)}) + \log(1 - D_{\phi}(G_{\theta}(\mathbf{z}^{(i)})))]$$

• Update the generator parameters $\boldsymbol{\theta}$ by stochastic gradient descent

$$\nabla_{\theta} V(G_{\theta}, D_{\phi}) = \frac{1}{m} \nabla_{\theta} \sum_{i=1}^{m} \log(1 - D_{\phi}(G_{\theta}(\mathbf{z}^{(i)})))$$

• Repeat for fixed number of epochs

$\min_{\theta} \max_{\phi} V(G_{\theta}, D_{\phi}) = E_{\mathbf{x} \sim p_{\text{data}}}[\log D_{\phi}(\mathbf{x})] + E_{\mathbf{z} \sim p(\mathbf{z})}[\log(1 - D_{\phi}(G_{\theta}(\mathbf{z})))]$



Frontiers in GAN research



- GANs have been successfully applied to several domains and tasks
- However, working with GANs can be very challenging in practice
 - Unstable optimization
 - Mode collapse
 - Evaluation
- Many bag of tricks applied to train GANs successfully

Optimization challenges

- **Theorem (informal):** If the generator updates are made in function space and discriminator is optimal at every step, then the generator is guaranteed to converge to the data distribution
- Unrealistic assumptions!
- In practice, the generator and discriminator loss keeps oscillating during GAN training



Source: Mirantha Jayathilaka

• No robust stopping criteria in practice (unlike MLE)

Mode Collapse

- GANs are notorious for suffering from mode collapse
- Intuitively, this refers to the phenomena where the generator of a GAN collapses to one or few samples (dubbed as "modes")



Arjovsky et al., 2017



• True distribution is a mixture of Gaussians



• The generator distribution keeps oscillating between different modes

Mode Collapse



- Fixes to mode collapse are mostly empirically driven: alternative architectures, alternative GAN loss, adding regularization terms, etc.
- https://github.com/soumith/ganhacks
 How to Train a GAN? Tips and tricks to make GANs work by Soumith Chintala

Beauty lies in the eyes of the discriminator



Source: Robbie Barrat, Obvious

GAN generated art auctioned at Christie's. **Expected Price:** \$7,000 - \$10,000 **True Price:** \$432,500